

# Abstracts

## An automated system for measuring power devices in Ka-band

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*B. Bonte, C. Gaquiere, E. Bourcier, G. Lemeur and Y. Crosnier. "An automated system for measuring power devices in Ka-band." 1998 Transactions on Microwave Theory and Techniques 46.1 (Jan. 1998 [T-MTT]): 70-75.*

An active load-pull system is presented for measuring devices from 50- $\Omega$  to 3-mm gatewidth in Ka-band. It can automatically scan the interesting area of the Smith chart. The system protects the tested devices because the impedance is presented at the output of the device only if the gate current is lower than a fixed value. Results are presented at 30 and 38 GHz on a pseudomorphic high electron-mobility transistor (PM-HEMT).

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